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Measuring methods for photodiodes of PIN,APD

PIN、雪崩光电二极管测试方法
(English Translation)

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What this standard covers

This Standard specifies the test methods PIN, avalanche photodiode (hereinafter referred to as "diode") photovoltaic parameters.

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Standards quoted by this document

GB/T 2421.1-2008; GB/T 11499-2001; GB/T 15651